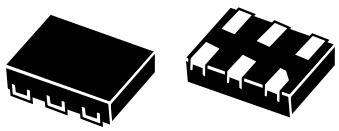
SR1

4 pin Smart Reset™

Datasheet - production data



UDFN6 (1.00 x 1.45 mm)

Applications

- Wearable
- Activity tracker
- Smartwatch
- Smartglasses

Features

- Operating voltage range 2 V to 5.5 V
- Low supply current 1 µA
- Integrated test mode
- Single Smart Reset™ push-button input with fixed extended reset setup delay (t_{SRC}) from 0.5 s to 10 s in 0.5 s steps (typ.), option with internal input pull-up resistor
- Push-button controlled reset pulse duration
  - Option 1: fully push-button controlled, no fixed or minimum pulse width guaranteed
  - Option 2: defined output reset pulse duration (t_{REC}), factory-programmed
- Single reset output
  - Active low or active high
  - Push-pull or open drain with optional pull-up resistor
- Fixed Smart Reset input logic voltage levels
- Operating temperature: -40 °C to +85 °C
- UDFN6 package 1.00 mm x 1.45 mm
- ECOPACK®2 (RoHS compliant, Halogen-Free)

Contents

1 Description

The Smart Reset™ devices provide a useful feature which ensures that inadvertent short reset push-button closures do not cause system resets. This is done by implementing an extended Smart Reset input delay time (t_{SRC}), which ensures a safe reset and eliminates the need for a specific dedicated reset button.

This reset configuration provides versatility and allows the application to distinguish between a software generated interrupt and a hard system reset. When the input push-button is connected to the microcontroller interrupt input, and is closed for a short time, the processor can only be interrupted. If the system still does not respond properly, continuing to keep the push-button closed for the extended setup time t_{SRC} causes a hard reset of the processor through the reset output.

The SR1 has one Smart Reset input ($\overline{SR}$) with preset delayed Smart Reset setup time (t_{SRC}). The reset output ($\overline{RST}$) is asserted after the Smart Reset input is held active for the selected t_{SRC} delay time. The $\overline{RST}$ output remains asserted either until the $\overline{SR}$ input goes to inactive logic level (i.e. neither fixed nor minimum reset pulse width is set) or the output reset pulse duration is fixed for t_{REC} (i.e. factory-programmed). The device fully operates over a broad V_{CC} range from 2.0 V to 5.5 V.

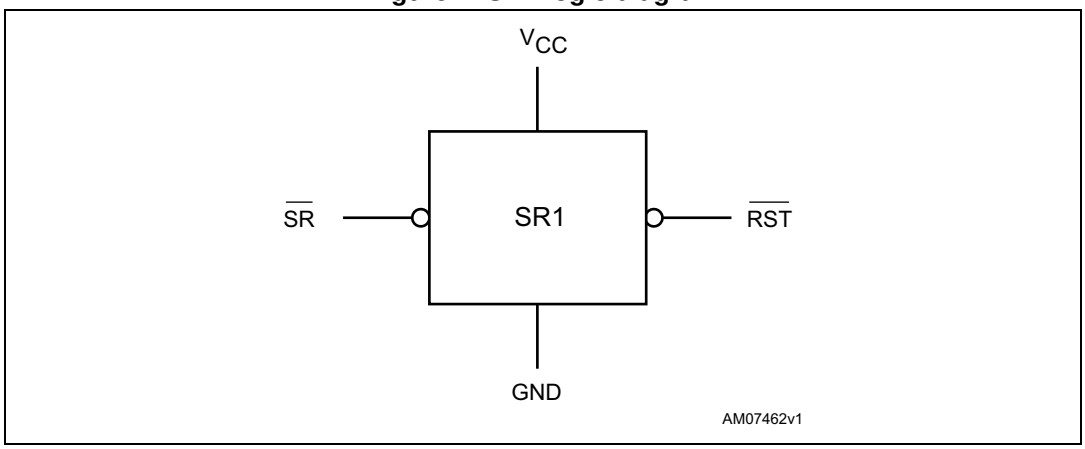
1.1 Test mode

After pulling $\overline{SR}$ up to V_{TEST} (V_{CC} + 1.4 V) or above, the counter starts to count the initial shortened $t_{SRC-INI}$ (42 ms, typ.). After $t_{SRC-INI}$ expires, the $\overline{RST}$ output either goes down for t_{REC} (if t_{REC} option is used) or stays low as long as overvoltage on $\overline{SR}$ is detected (if t_{REC} option is not used). This is feedback, and the user only knows that the device is locked in test mode. Each time the $\overline{SR}$ input is connected to ground in test mode, a shortened $t_{SRC-SHORT}$ (t_{SRC}/128) is used instead of regular t_{SRC} (0.5 s - 10 s). In this way the device can be quickly tested without repeating test mode triggering. Return to normal mode is possible by performing a new startup of the device (i.e. V_{CC} goes to 0 V and back to its original state).

The advantages of this solution are its high glitch immunity, user feedback regarding entry into test mode, and testability within the full V_{CC} range.

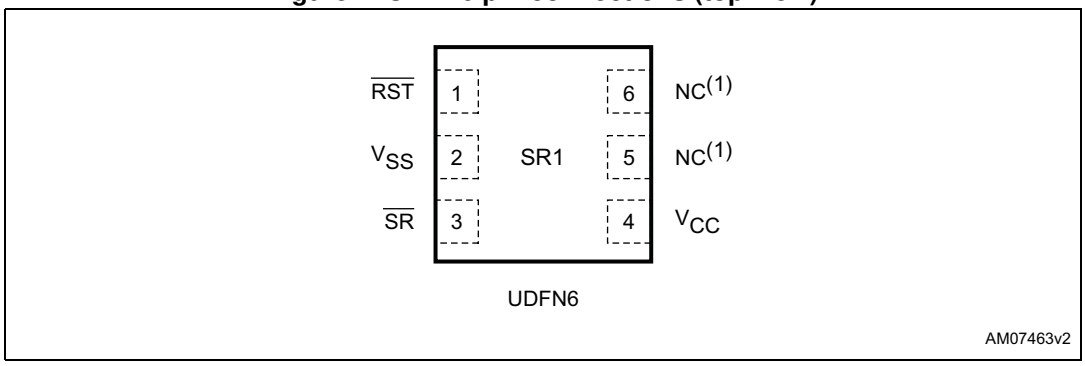
1.2 Logic diagram

Figure 1. SR1 logic diagram



1.3 Pin connections

Figure 2. UDFN6 pin connections (top view)



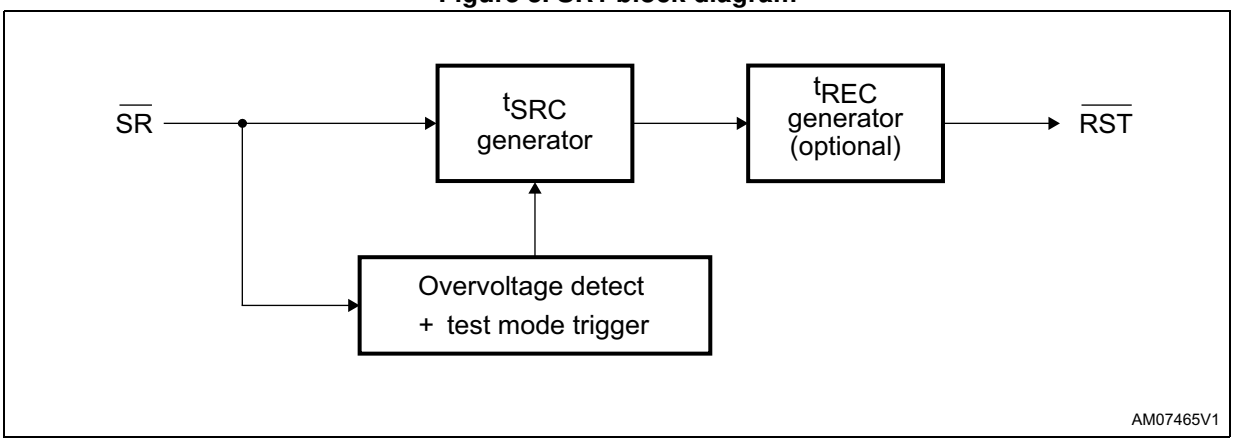
1. Not connected (not bonded); should be connected to V_{SS}.

2 Device overview

Table 1. Signal names

Pin n°	Name	Type	Description
1	$\overline{RST}$	Output	Reset output, active low, open drain.
2	V_{SS}	Supply ground	Ground
3	$\overline{SR}$	Input	Smart Reset input, active low.
4	V_{CC}	Supply voltage	Positive supply voltage for the device. A 0.1 µF decoupling ceramic capacitor is recommended to be connected between V_{CC} and V_{SS} pins.
5	NC	-	Not connected (not bonded); should be connected to V_{SS}.
6	NC	-	Not connected (not bonded); should be connected to V_{SS}.

Figure 3. SR1 block diagram



3 Pin descriptions

3.1 Power supply (V_{CC})

This pin is used to provide power to the Smart Reset device. A 0.1 µF ceramic decoupling capacitor is recommended to be connected between the V_{CC} and V_{SS} pins, as close to the SR1 device as possible.

3.2 Power-up sequence

In normal mode, if different input side ($\overline{SR}$) and V_{CC} voltage domains are used, power-on sequence must avoid meeting the test mode entry condition to avoid inadvertent test mode entry: there should not be logic high present on the $\overline{SR}$ input before the V_{CC} power-up. However V_{CC} and V($\overline{SR}$) rising at the same time is OK (e.g. if both are in the same voltage domain), the device will then safely start into normal operating mode, with $\overline{RST}$ output inactive (in High-Z mode for open-drain option).

3.3 Ground (V_{SS})

This is the ground pin for the device.

3.4 Smart Reset input ($\overline{SR}$)

Push-button Smart Reset input, active low with optional pull-up resistor. $\overline{SR}$ input needs to be asserted for at least t_{SRC} to assert the reset output ($\overline{RST}$).

By connecting a voltage higher than V_{CC} + 1.4 V to the $\overline{SR}$ input the device enters test mode (see *Section 1: Description on page 3* for more information).

3.5 Reset output ($\overline{RST}$)

$\overline{RST}$ is active low or active high, open drain or push-pull reset output with optional internal pull-up resistor.

Output reset pulse width is optional as follows:

- Neither fixed nor minimum output reset pulse duration (releasing the push-button while reset output is active, causes the output to de-assert)
- Fixed, factory-programmed output reset pulse duration for t_{REC} independent on Smart Reset input state.

3.6 $\overline{RST}$ output undervoltage behavior (for open-drain option)

High-Z on $\overline{RST}$ output below the specified operating voltage range is guaranteed at V_{CC} power-on or in case that valid V_{CC} dropped while the device was idle, i.e. while both output and input were inactive.

4 Typical application diagrams

Figure 4. Typical application diagram - input, output and SR1 device in one voltage domain

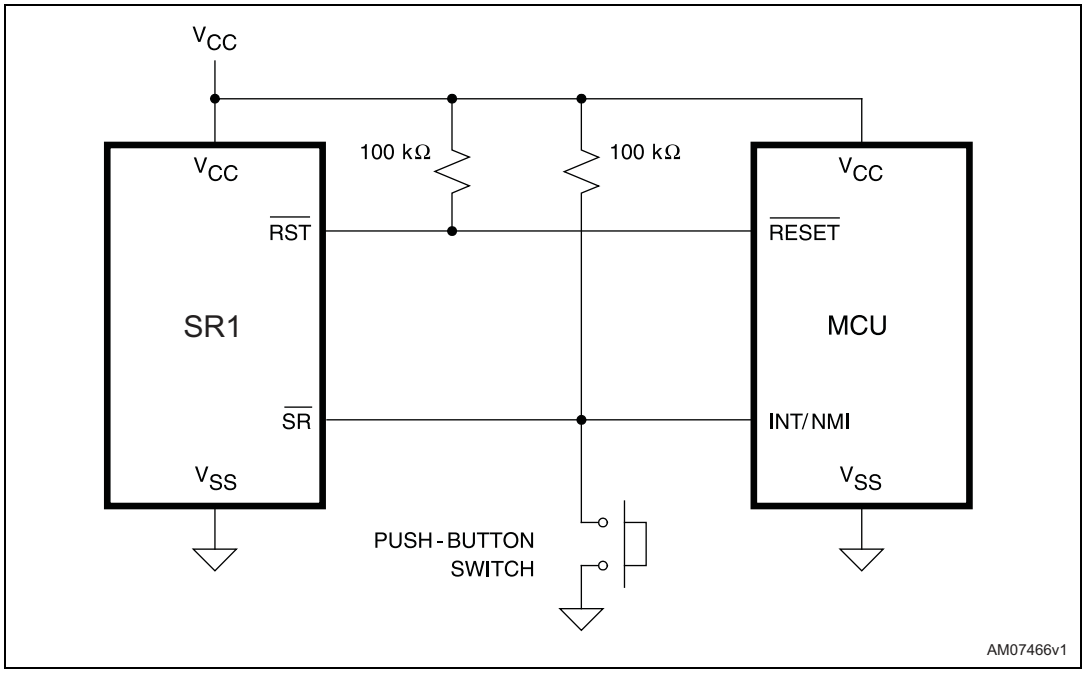
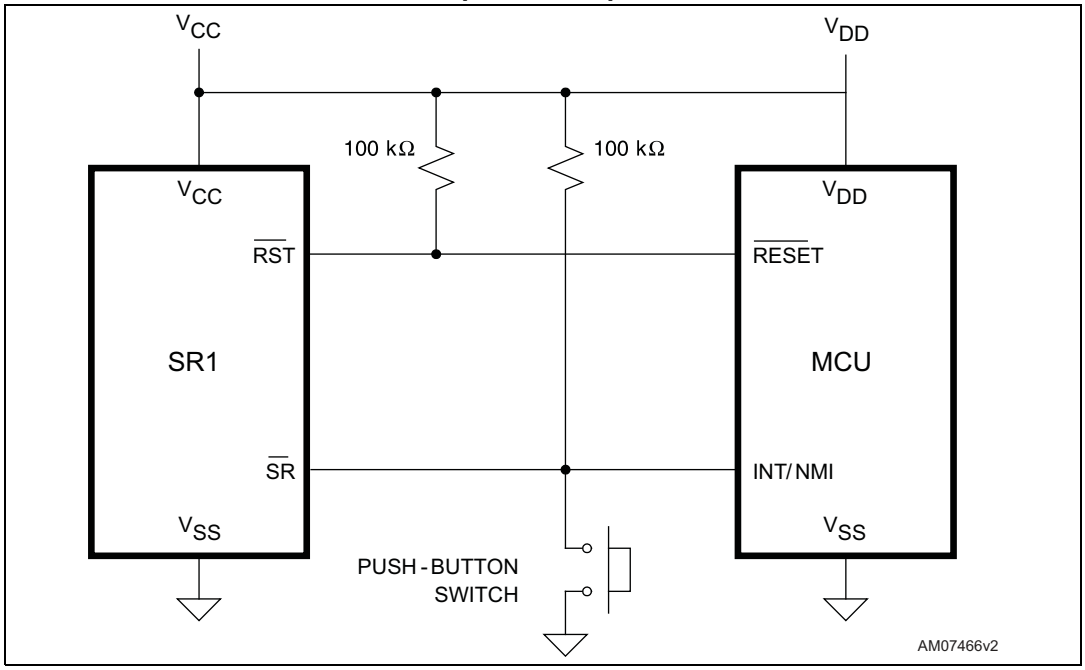
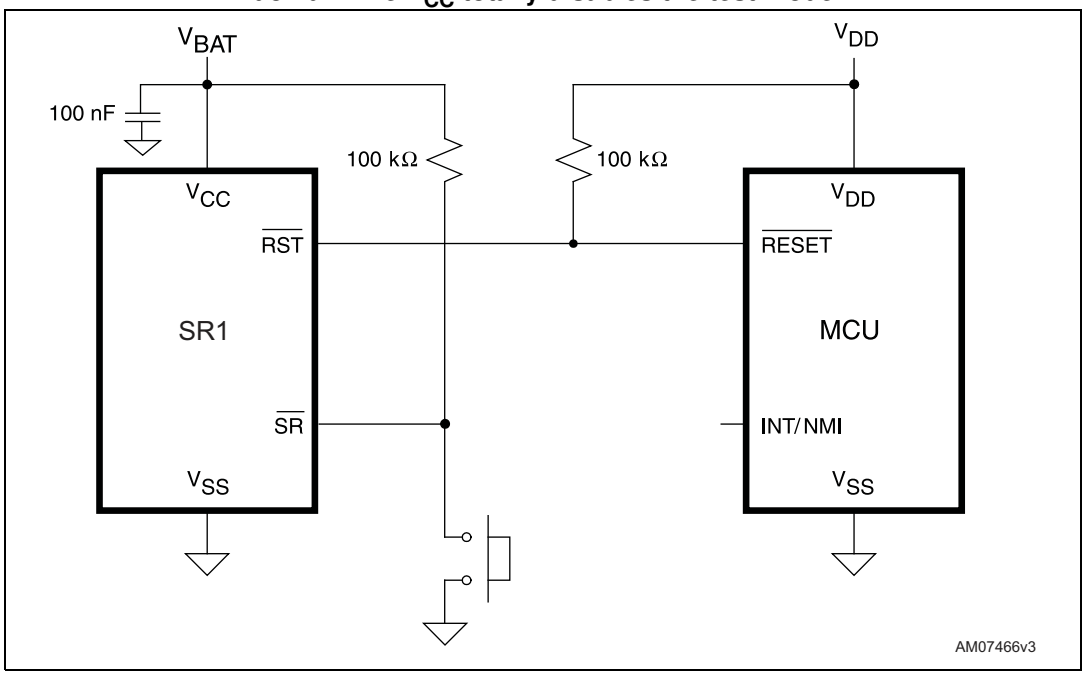


Figure 5. Typical application diagram - SR1 device in a different voltage domain than input and output



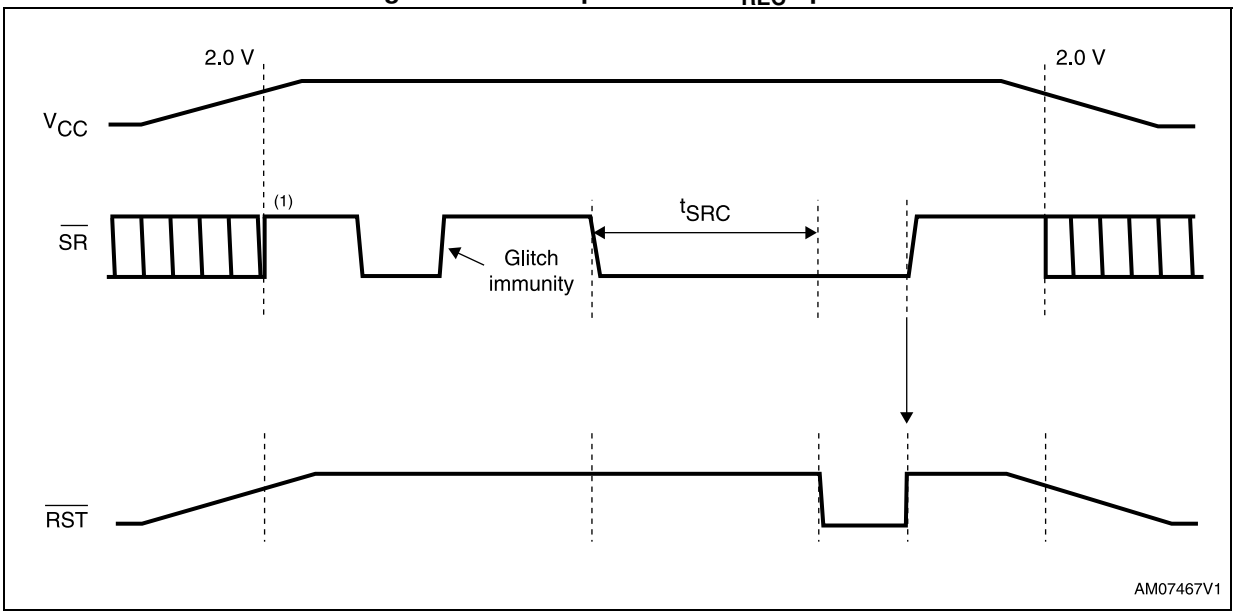
1. Open-drain $\overline{RST}$ output type and fixed $\overline{SR}$ input logic threshold allows to use the device in different voltage domains. To prevent entering test mode by creating a condition V($\overline{SR}$) > V_{CC} + 1.1 V typ., V_{CC} should be powered up before or together with voltage on the $\overline{SR}$ input.

Figure 6. Typical application diagram in different voltage domains - $\overline{SR}$ input in V_{BAT} domain like V_{CC} totally disables the test mode



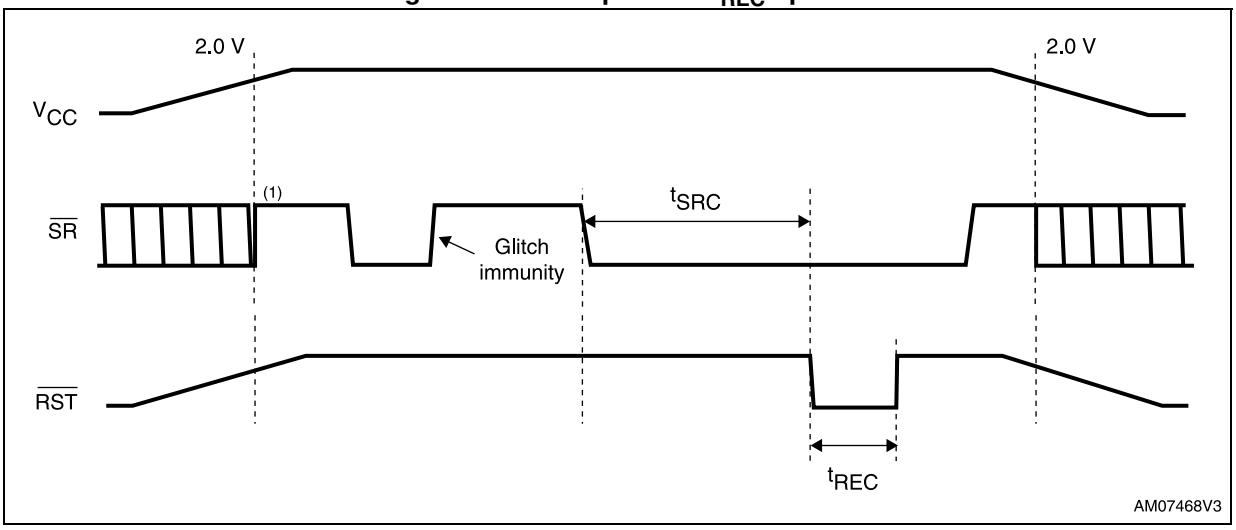
5 Timing diagrams

Figure 7. $\overline{RST}$ output without t_{REC} option



1. V_{CC} should be powered up before or together with voltage on the $\overline{SR}$ input to prevent entering test mode by creating a condition $V(\overline{SR}) > V_{CC}$ +1.1 V typ.

Figure 8. $\overline{RST}$ output with t_{REC} option



1. V_{CC} should be powered up before or together with voltage on the $\overline{SR}$ input to prevent entering test mode by creating a condition $V(\overline{SR}) > V_{CC}$ +1.1 V typ.

6 Typical operating characteristics

Figure 9. Supply current (I_{CC}) vs. temperature (T_A)

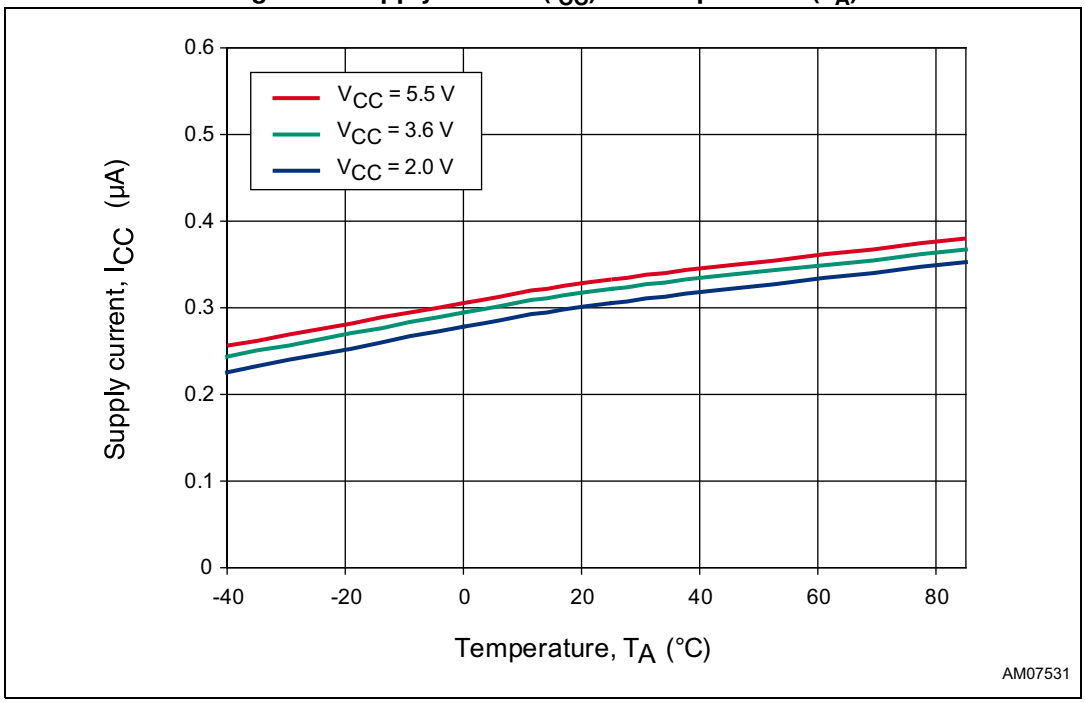


Figure 10. Smart Reset delay (t_{SRC}) vs. temperature (T_A), t_{SRC} = 4.0 s (typ.)

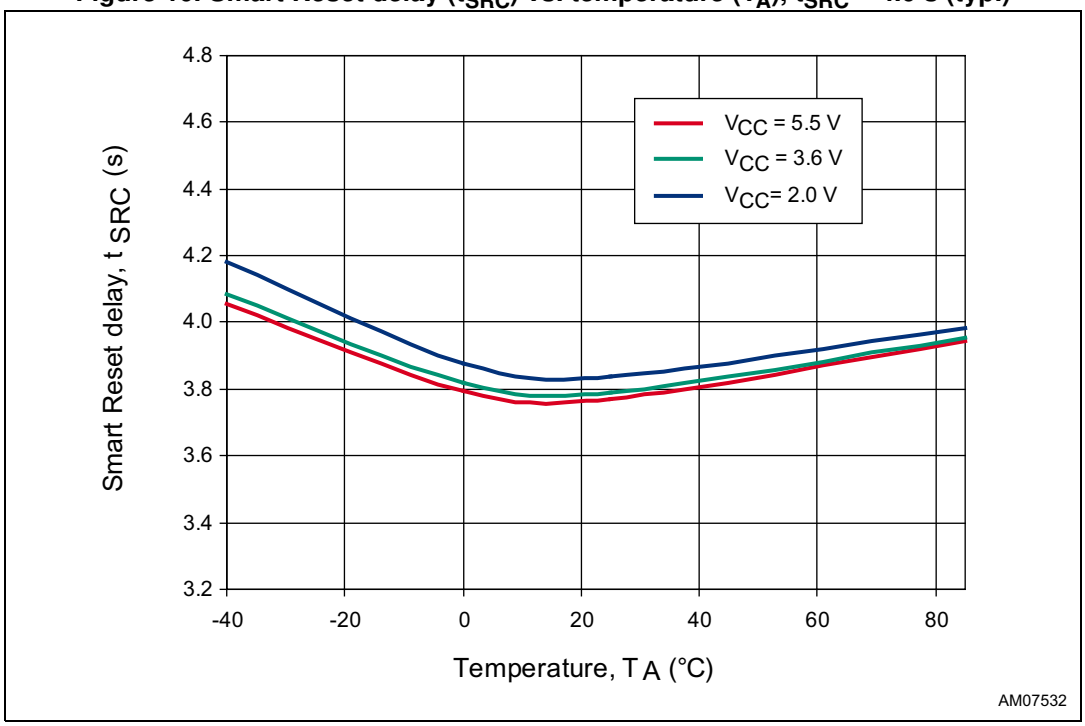


Figure 11. Test mode entry voltage (V_{TEST}) vs. temperature (T_A)

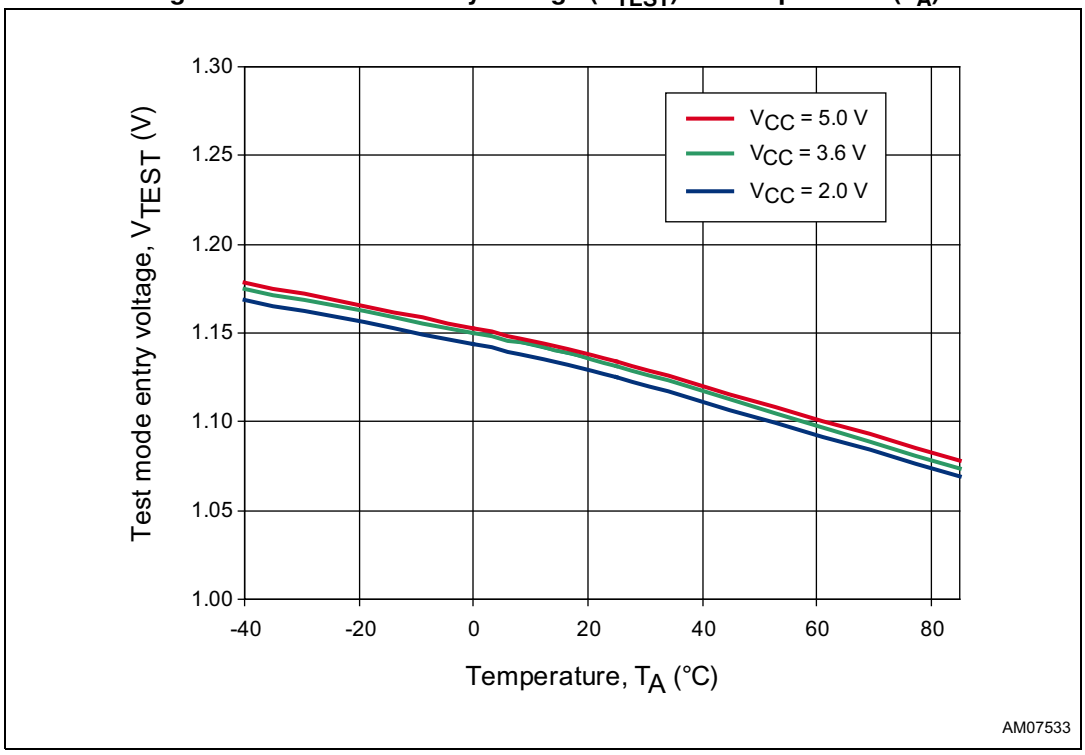
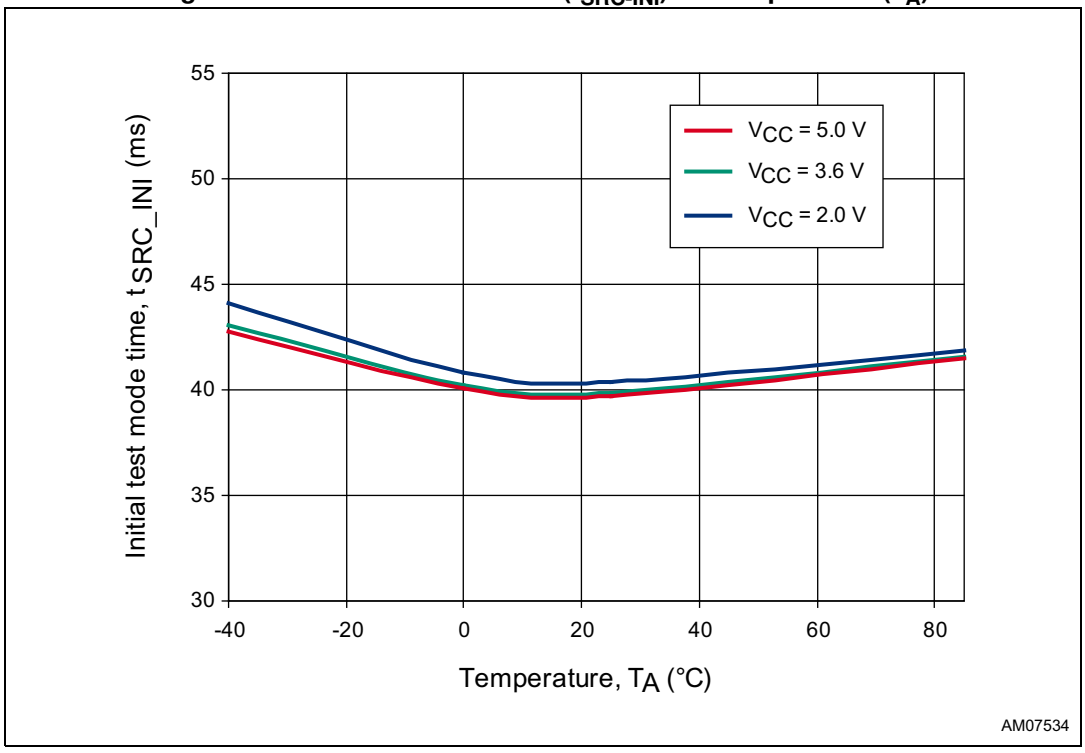


Figure 12. Initial test mode time ($t_{SRC-INI}$) vs. temperature (T_A)



7 Maximum ratings

Stressing the device above the rating listed in *Table 2: Absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in *Table 3: Operating and measurement conditions* of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Refer also to the STMicroelectronics™ SURE program and other relevant quality documents.

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
T_{STG}	Storage temperature (V_{CC} off)	-55 to +150	°C
T_{SLD}(1)	Lead solder temperature for 10 seconds	260	°C
V_{IO}	Input or output voltage	-0.3 to 5.5	V
V_{CC}	Supply voltage	-0.3 to 7	V
ESD			
V_{HBM}	Electrostatic discharge protection, human body model (JESD22-A114-B level 2)	2	kV
V_{RCDM}	Electrostatic discharge protection, charged device model, all pins	1	kV
V_{MM}	Electrostatic discharge protection, machine model, all pins (JESD22-A115-A level A)	200	V
	Latch-up (V_{CC} pin, $\overline{SR}$ reset input pin)	EIA/JESD78	

1. Reflow at peak temperature of 260 °C. The time above 255 °C must not exceed 30 seconds.

8 DC and AC parameters

This section summarizes the operating measurement conditions, and the DC and AC characteristics of the device. The parameters in *Table 4: DC and AC characteristics* are derived from tests performed under the measurement conditions summarized in *Table 3: Operating and measurement conditions*. Designers should check that the operating conditions in their circuit match the operating conditions when relying on the quoted parameters.

Table 3. Operating and measurement conditions

Symbol	Parameter	Value	Unit
V_{CC}	Supply voltage	2.0 to 5.5	V
T_A	Ambient operating temperature	-40 to +85	°C
t_R, t_F	Input rise and fall times	≤ 5	ns
	Input pulse voltages	0.2 to 0.8 V_{CC}	V
	Input and output timing reference voltages	0.3 to 0.7 V_{CC}	V

Table 4. DC and AC characteristics

Symbol	Parameter	Test conditions[1]	Min.	Typ.[2]	Max.	Unit
V_{CC}	Supply voltage		2.0		5.5	V
I_{CC}	Supply current	$\overline{SR}$ = V_{CC}, t_{REC} and t_{SRC} counter is not running		0.4	1.0	µA
V_{OL}	Reset output voltage low	$V_{CC} \geq$ 4.5 V, sinking 3.2 mA			0.3	V
		$V_{CC} \geq$ 3.3 V, sinking 2.5 mA			0.3	V
		$V_{CC} \geq$ 2.0 V, sinking 1 mA			0.3	V
t_{REC}	Reset timeout delay, factory-programmed	(device option)	140	210	280	ms
			240	360	480	ms
R_{PUO}	Internal output pull-up resistor on $\overline{RST}$	(device option)		65		kΩ
I_{LO}	Output leakage current	$V_{\overline{RST}}$ = 5.5 V, open drain device option without output pull-up resistor	-0.1		0.1	µA
Smart Reset						
t_{SRC}	Smart Reset delay	T_A = -40 to +85 °C	0.8 x t_{SRC}	t_{SRC}[3]	1.2 x t_{SRC}	s
		T_A = 25 °C	0.9 x t_{SRC}		1.1 x t_{SRC}	
V_{IL}	$\overline{SR}$ input voltage low		V_{SS}-0.3		0.3	V
V_{IH}	$\overline{SR}$ input voltage high		0.85		5.5	V
R_{PUI}	Internal input pull-up resistor on $\overline{SR}$	(device option)		65		kΩ
I_{LEAK}	$\overline{SR}$ input leakage current	device option without input pull-up resistor	-0.1		0.1	µA
	Input glitch immunity			t_{SRC}		s
Test mode						
V_{TEST}	Test mode entry voltage		V_{CC} +0.9	V_{CC} +1.1	V_{CC} +1.4	V
$t_{SRC-INI}$	Initial test mode time		28	42	56	ms
$t_{SRC-SHORT}$	Shortened Smart Reset delay			t_{SRC} / 128		ms

1. Valid for ambient operating temperature T_A = -40 to +85 °C, V_{CC} = 2.0 to 5.5 V.
2. Typical values are at 25 °C and V_{CC} = 3.3 V unless otherwise noted.
3. Factory-programmable in the range of 0.5 s to 10 s typ. in 0.5 s steps.

9 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK is an ST trademark.

Figure 13. UDFN6, (1.00 x 1.45 x 0.50 mm), 0.50 mm pitch package outline

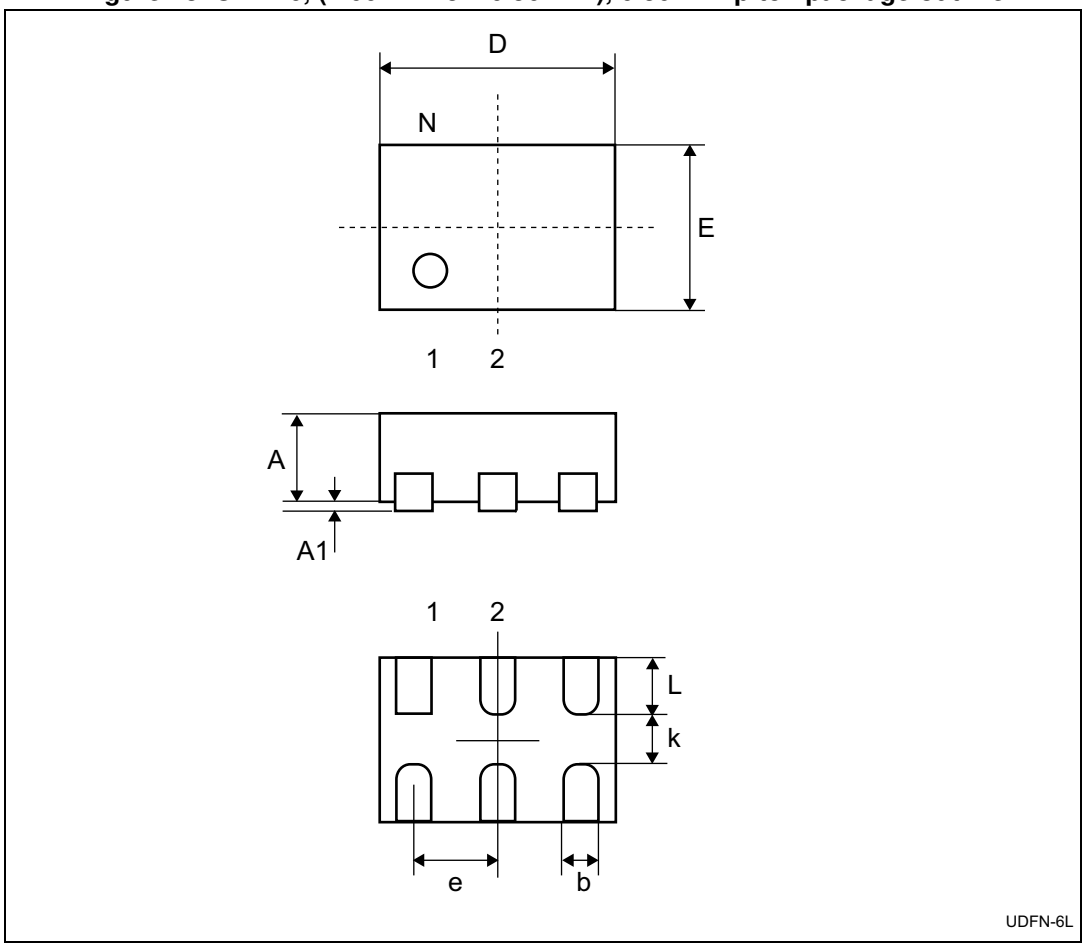
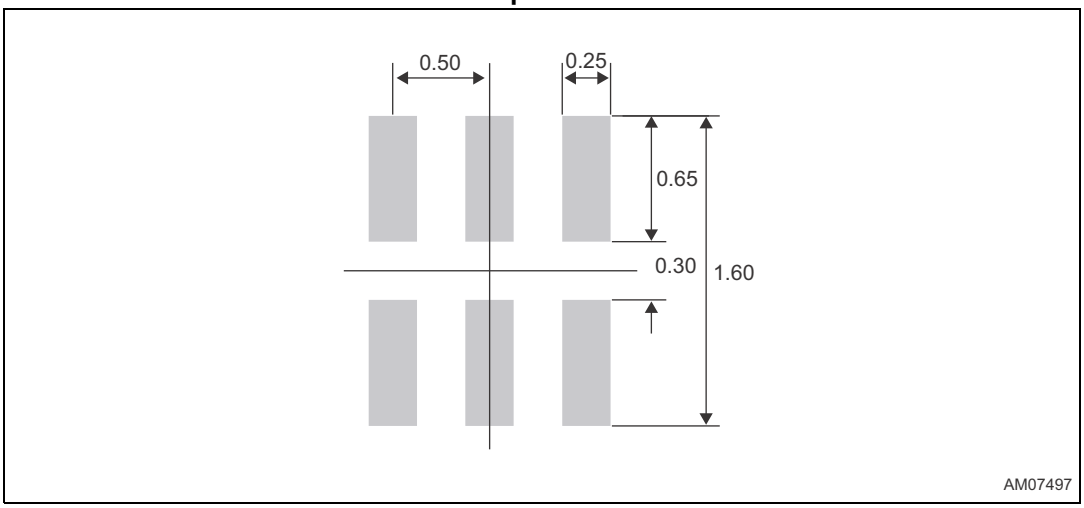


Table 5. UDFN6, (1.00 x 1.45 x 0.50 mm), 0.50 mm pitch package mechanical data

Symbol	Dimensions						Note(1)
	(mm)			(inches)			
	Min.	Typ.	Max.	Min.	Typ.	Max.	
A	0.50	0.55	0.60	0.0197	0.0217	0.0236	
A1	0.00	0.02	0.05	0.000	0.0008	0.0020	
b	0.18	0.25	0.30	0.0071	0.0098	0.0118	
D	1.40	1.45	1.50	0.0551	0.0571	0.0591	
E	0.95	1.00	1.05	0.0374	0.0394	0.0413	
e	0.45	0.50	0.55	0.0177	0.0197	0.0217	
k	0.20			0.0079			
L	0.30	0.35	0.40	0.0118	0.0138	0.0157	

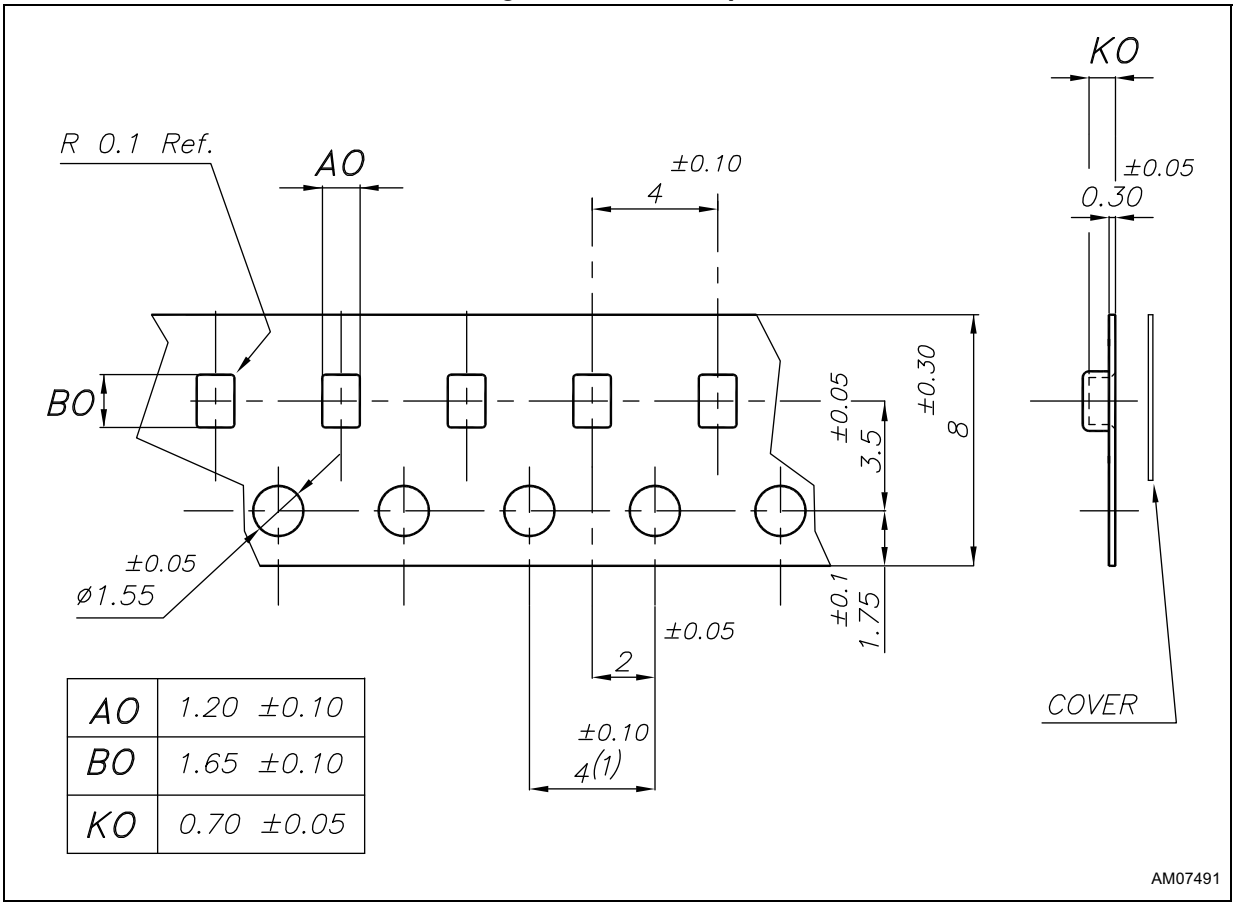
1. Package outline exclusive of any mold flashes dimensions and metal burrs.

Figure 14. Footprint recommendation for UDFN6 (1.00 x 1.45 x 0.50 mm), 0.50 mm pitch



10 Tape and reel information

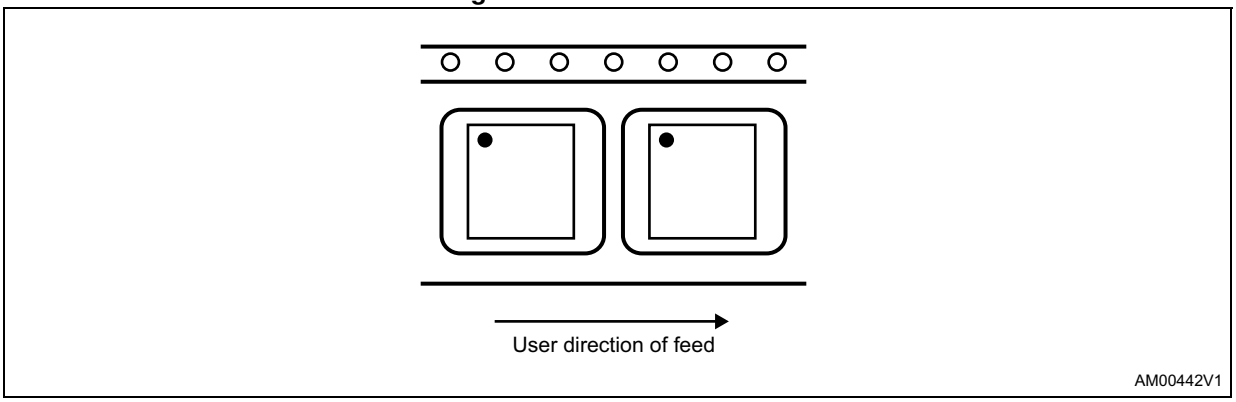
Figure 15. Carrier tape



AO	1.20 ±0.10
BO	1.65 ±0.10
KO	0.70 ±0.05

1. 10-sprocket hole pitch cumulative tolerance ±0.20.

Figure 16. Pin 1 orientation



11 Part numbering

Table 6. Ordering information scheme

Example: SR1 H A R U

Device type

SR1

Smart Reset setup delay (t_{SRC})(1)

C = factory programmable t_{SRC} = 1.5 s (typ.)

H = factory programmable t_{SRC} = 4.0 s (typ.)

L = factory programmable t_{SRC} = 6.0 s (typ.)

P = factory programmable t_{SRC} = 7.5 s (typ.)

U = factory programmable t_{SRC} = 10.0 s (typ.)

Inputs, outputs type(2)

A = active low $\overline{SR}$ input with no pull-up,
active low open drain $\overline{RST}$ output with no pull-up

B = active low $\overline{SR}$ input with pull-up,
active low open drain $\overline{RST}$ output with no pull-up

Reset timeout period (t_{REC})

A = factory programmable t_{REC} = 210 ms (typ.)

B = factory programmable t_{REC} = 360 ms (typ.)

R = push-button controlled (no defined t_{REC})

Package

U = UDFN-6L

1. Smart Reset delay (t_{SRC}) is available from 0.5 s to 10 s in 0.5 s steps (typ.). Minimum order quantities may apply. Contact local sales office for availability.
2. Push-pull reset output type also available (active low or active high). $\overline{SR}$ input and open drain reset output available with optional pull-up resistor. Minimum order quantities may apply. Contact local sales office for availability.

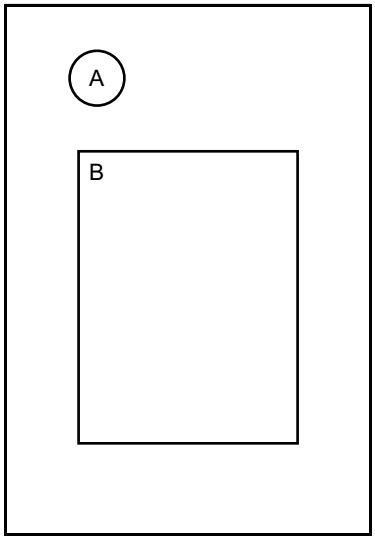
12 Package marking information

Table 7. Package marking

Part number	t_{SRC} (s)	Smart Reset inputs(1)	Output type(2)	t_{REC} option(3)	Package	Topmark
SR1CARU	1.5	AL	OD, AL	No t_{REC}	UDFN6	CA
SR1HARU	4.0	AL	OD, AL	No t_{REC}	UDFN6	HA
SR1LARU	6.0	AL	OD, AL	No t_{REC}	UDFN6	LA
SR1PAAU	7.5	AL	OD, AL	210 ms	UDFN6	PB
SR1PARU	7.5	AL	OD, AL	No t_{REC}	UDFN6	PA
SR1PBBU	7.5	AL + pull-up	OD, AL	360 ms	UDFN6	PC
SR1UARU	10.0	AL	OD, AL	No t_{REC}	UDFN6	UA

1. AL = active low.
2. OD = open drain, AL = active low.
3. No t_{REC} = push-button controlled reset pulse width, any other value represents typical value of t_{REC}.

Figure 17. Package marking (top view)



A = dot (pin 1 reference)
B = marking area (topmark)

GAPMSMD00037

13 Revision history

Table 8. Document revision history

Date	Revision	Changes
10-Mar-2014	1	Initial release
13-May-2014	2	Modified t_{REC} values *Table 4 on page 14*

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